

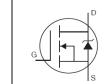
# infineon

# AUIRFR4105Z AUIRFU4105Z

HEXFET<sup>®</sup> Power MOSFET

# Features

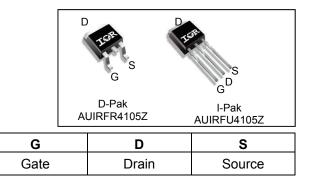
- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified \*



	V <sub>DSS</sub>		55V
)	R <sub>DS(on)</sub>	max.	24.5mΩ
	I <sub>D</sub>		30A



Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



Bass part number	Dookogo Tupo	Standard Pack		Orderable Part Number	
Base part number	Package Type	Form	Quantity	Orderable Part Number	
AUIRFU4105Z	I-Pak	Tube	75	AUIRFU4105Z	
AUIRFR4105Z	D Dek	Tube	75	AUIRFR4105Z	
AUIKER41052	D-Pak	Tape and Reel Left	3000	AUIRFR4105ZTRL	

# Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	30	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	21	A
I <sub>DM</sub>	Pulsed Drain Current ①	120	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	48	W
	Linear Derating Factor	0.32	W/°C
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally Limited) 2	29	
E <sub>AS</sub> (Tested)	Single Pulse Avalanche Energy Tested Value 6	46	mJ
I <sub>AR</sub>	Avalanche Current ①	See Fig.15,16, 12a, 12b	A
E <sub>AR</sub>	Repetitive Avalanche Energy S		mJ
TJ	Operating Junction and	-55 to + 175	
T <sub>STG</sub>	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

# Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
R <sub>θJC</sub>	Junction-to-Case ®		3.12	
$R_{ heta JA}$	Junction-to-Ambient (PCB Mount) 🗇		50	°C/W
$R_{ ext{ heta}JA}$	Junction-to-Ambient		110	

HEXFET® is a registered trademark of Infineon.

\*Qualification standards can be found at www.infineon.com



p-n junction diode.

### Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	55			V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA
$\Delta V_{(BR)DSS} / \Delta T_J$	Breakdown Voltage Temp. Coefficient		0.053		V/°C	Reference to 25°C, $I_D$ = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		19	24.5	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 18A
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0		4.0	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA
gfs	Forward Trans conductance	16			S	V <sub>DS</sub> = 15V, I <sub>D</sub> = 18A
1	Drain-to-Source Leakage Current			20		V <sub>DS</sub> = 55V, V <sub>GS</sub> = 0V
I <sub>DSS</sub>	Drain-to-Source Leakage Current			250	μΑ	V <sub>DS</sub> = 55V,V <sub>GS</sub> = 0V,T <sub>J</sub> =125°C
1	Gate-to-Source Forward Leakage			200	<b>n</b> ^	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-200	nA	V <sub>GS</sub> = -20V

#### Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

$Q_{g}$	Total Gate Charge		18	27		I <sub>D</sub> = 18A
$Q_{gs}$	Gate-to-Source Charge		5.3		nC	$V_{DS} = 44V$
Q <sub>gd</sub>	Gate-to-Drain Charge		7.0			V <sub>GS</sub> = 10V③
t <sub>d(on)</sub>	Turn-On Delay Time		10			V <sub>DD</sub> = 28V
tr	Rise Time		40		-	I <sub>D</sub> = 18A
t <sub>d(off)</sub>	Turn-Off Delay Time		26		ns	R <sub>G</sub> = 24.5Ω
t <sub>f</sub>	Fall Time		24			V <sub>GS</sub> = 10V③
L <sub>D</sub>	Internal Drain Inductance		4.5			Between lead, 6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		7.5			from package and center of die contact
C <sub>iss</sub>	Input Capacitance		740			V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance		140			V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance		74		pF	<i>f</i> = 1.0MHz
C <sub>oss</sub>	Output Capacitance		450		рі	$V_{GS} = 0V, V_{DS} = 1.0V f = 1.0MHz$
C <sub>oss</sub>	Output Capacitance		110			$V_{GS} = 0V, V_{DS} = 44V f = 1.0MHz$
C <sub>oss eff.</sub>	Effective Output Capacitance		180			$V_{GS}$ = 0V, $V_{DS}$ = 0V to 44V ④
Diode Chai	racteristics					
	Parameter	Min.	Тур.	Max.	Units	Conditions
ls	Continuous Source Current (Body Diode)			30		MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current			120	A	integral reverse

Diode Forward Voltage 1.3 V T<sub>J</sub> = 25°C,I<sub>S</sub> = 18A, V<sub>GS</sub> = 0V ③  $V_{SD}$ 29 T<sub>.</sub>I = 25°C ,I<sub>F</sub> = 18A, V<sub>DD</sub> = 28V Reverse Recovery Time 19 ns l<sub>rr</sub> Qrr **Reverse Recovery Charge** 14 21 nC di/dt = 100A/µs③ Forward Turn-On Time Intrinsic turn-on time is negligible (turn-on is dominated by Ls+LD) t<sub>on</sub>

Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)

 $\odot$  Limited by T<sub>Jmax</sub>, starting T<sub>J</sub> = 25°C, L = 0.18mH, R<sub>G</sub> = 25 $\Omega$ , I<sub>AS</sub> = 18A, V<sub>GS</sub> =10V. Part not recommended for use above this value.

③ Pulse width  $\leq$  1.0ms; duty cycle  $\leq$  2%.

(Body Diode) ①

④ Coss eff. is a fixed capacitance that gives the same charging time as Coss while VDS is rising from 0 to 80% VDSS

© Limited by T<sub>Jmax</sub>, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.

(i) This value determined from sample failure population, starting  $T_J = 25^{\circ}C$ , L = 0.18mH,  $R_G = 25\Omega$ ,  $I_{AS} = 18A$ ,  $V_{GS} = 10V$ .

When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to 0 application note #AN-994

8  $R_{\theta}$  is measured at T<sub>J</sub> approximately 90°C.



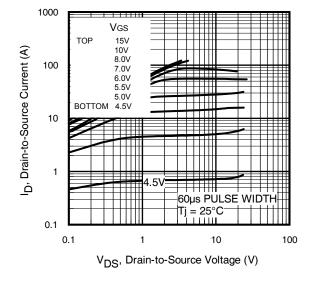


Fig. 1 Typical Output Characteristics

Fig. 2 Typical Output Characteristics

V<sub>DS</sub>, Drain-to-Source Voltage (V)

100

10

1000

100

10

1

0.1

I<sub>D</sub>, Drain-to-Source Current (A)

Vgs

TOP

BOTTOM

15V

10V 8.0V 7.0V 6.0V 5.5V 5.0V

4.5V

1

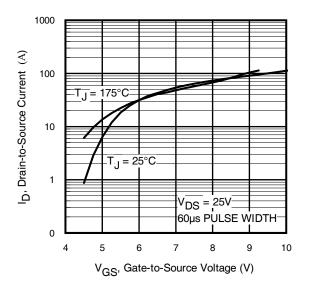


Fig. 3 Typical Transfer Characteristics

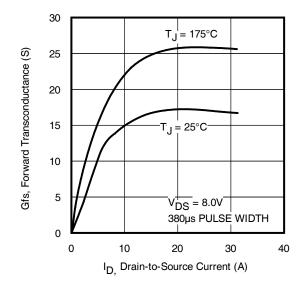
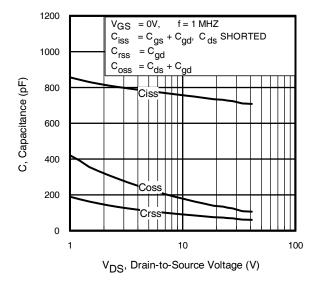
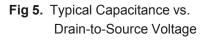


Fig. 4 Typical Forward Trans conductance Vs. Drain Current







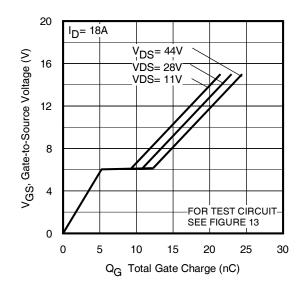


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

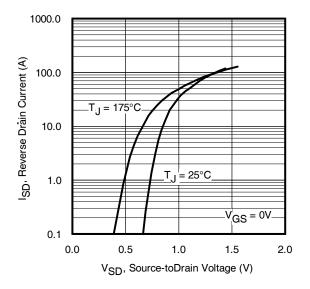


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

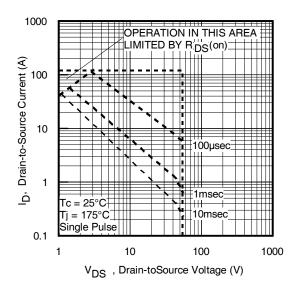
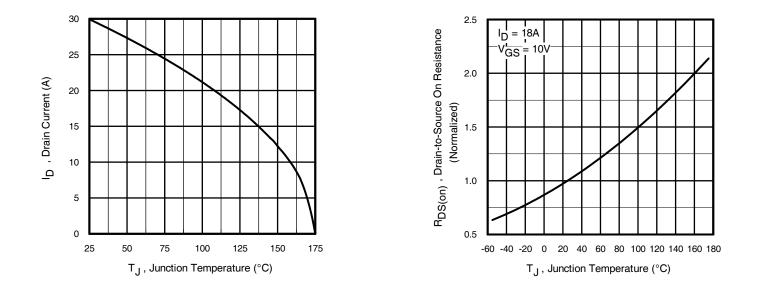
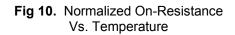


Fig 8. Maximum Safe Operating Area









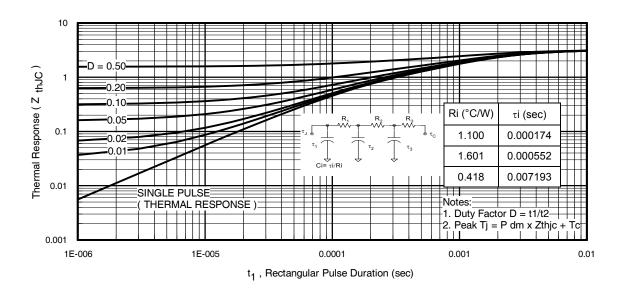


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

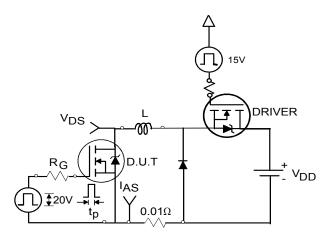
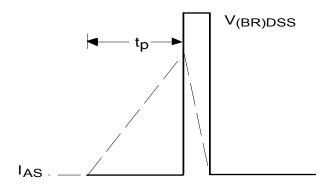
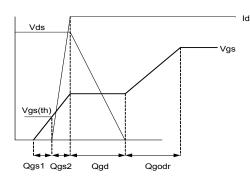


Fig 12a. Unclamped Inductive Test Circuit



## Fig 12b. Unclamped Inductive Waveforms



# Fig 13a. Gate Charge Waveform

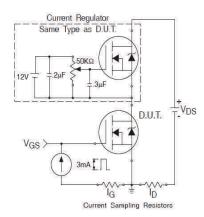
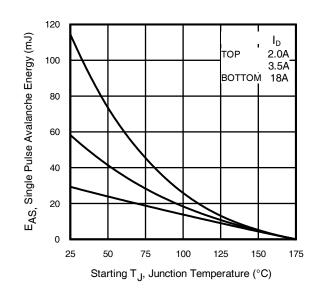
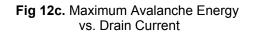


Fig 13b. Gate Charge Test Circuit





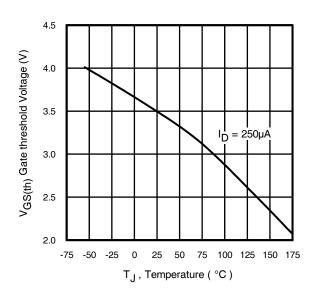


Fig 14. Threshold Voltage Vs. Temperature



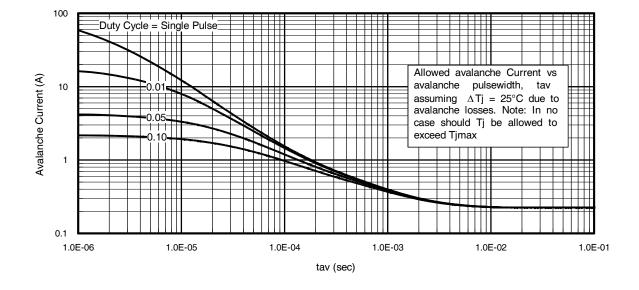


Fig 15. Typical Avalanche Current Vs. Pulse width

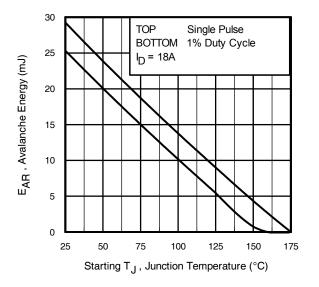


Fig 16. Maximum Avalanche Energy Vs. Temperature

#### Notes on Repetitive Avalanche Curves , Figures 15, 16:

(For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>imax</sub>. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as Tjmax is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. Iav = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed T<sub>jmax</sub> (assumed as 25°C in Figure 15, 16).

tav = Average time in avalanche.

D = Duty cycle in avalanche =  $t_{av} \cdot f$ 

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} \textbf{P}_{D (ave)} &= 1/2 \; ( \; 1.3 \cdot \textbf{BV} \cdot \textbf{I}_{av}) = \Delta T / \; \textbf{Z}_{thJC} \\ \textbf{I}_{av} &= 2 \Delta T / \; \textbf{[} 1.3 \cdot \textbf{BV} \cdot \textbf{Z}_{th} \textbf{]} \\ \textbf{E}_{AS (AR)} &= \textbf{P}_{D (ave)} \cdot \textbf{t}_{av} \end{split}$$

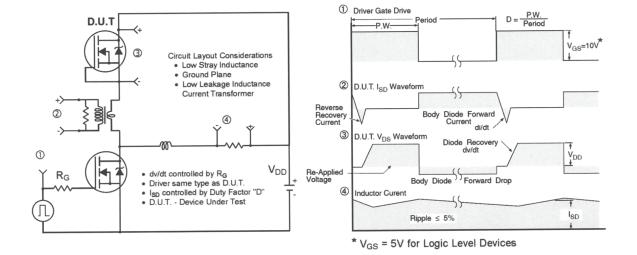


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

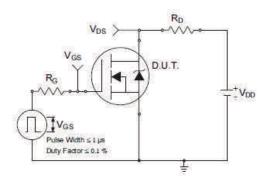


Fig 18a. Switching Time Test Circuit

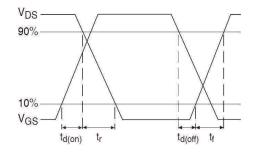
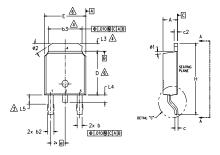


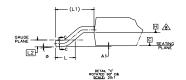
Fig 18b. Switching Time Waveforms

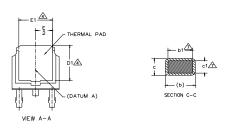


# D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))









- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- A- LEAD DIMENSION UNCONTROLLED IN 15.
- A- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.- SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- A- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- NLY.
- LANE H. AA.

_			1 APPLIED BE DETER			
			S TO JEDE			
S Y M		N				
B O	MILLIM	ETERS	INC	HES	0 T	
0 L	MIN.	MAX.	MIN.	MAX.	E S	
Α	2.18	2.39	.086	.094		
A1	-	0.13	-	.005		
b	0.64	0.89	.025	.035		
b1	0.65	0.79	.025	.031	7	
b2	0.76	1.14	.030	.045		
b3	4.95	5.46	.195	.215	4	
с	0.46	0.61	.018	.024		
c1	0.41	0.56	.016	.022	7	
c2	0.46	0.89	.018	.035		
D	5.97	6.22	.235	.245	6	
D1	5.21	-	.205	-	4	
Е	6.35	6.73	.250	.265	6	
E1	4.32	-	.170	-	4	
е	2.29	BSC	.090	BSC		
н	9.40	10.41	.370	.410		
L	1.40	1.78	.055	.070		
L1	2.74		.108	REF.		
L2		BSC	.020	BSC		
L3	0.89	1.27	.035	.050	4	
L4	-	1.02	-	.040		
L5	1.14	1.52	.045	.060	3	

LEAD ASSIGNMENTS

<u>HEXFET</u>

1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN

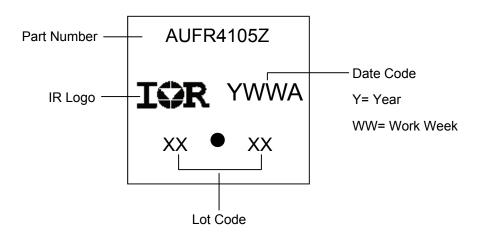
IGBT & CoPAK

1.- GATE

2.- COLLECTOR 3.- EMITTER

4.- COLLECTOR

#### D-Pak (TO-252AA) Part Marking Information



ø 0\*

ø1 0'

ø2 25' 10**°** 

15°

35'

0\*

0'

25'

10°

15°

35'

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



# I-Pak (TO-251AA) Package Outline (Dimensions are shown in millimeters (inches)

NOTES:

1

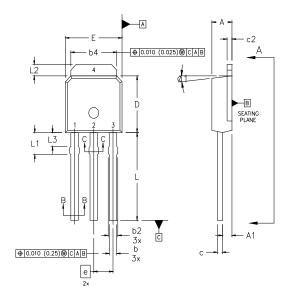
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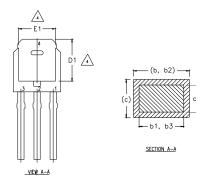
3

5

/6\

8





		DIMEN	SIONS		
SYMBOL	MILLIMETERS		INC	HES	
	Min.	MAX.	MIN.	MAX.	NOTES
А	2.18	2.39	0.086	.094	
A1	0.89	1.14	0.035	0.045	
b	0.64	0.89	0.025	0.035	
ь1	0.64	0.79	0.025	0.031	4
b2	0.76	1.14	0.030	0.045	
b3	0.76	1.04	0.030	0.041	
b4	5.00	5.46	0.195	0.215	4
с	0.46	0.61	0.018	0.024	
c1	0.41	0.56	0.016	0.022	
c2	.046	0.86	0.018	0.035	
D	5.97	6.22	0.235	0.245	3, 4
D1	5.21	-	0.205	-	4
E	6.35	6.73	0.250	0.265	3, 4
E1	4.32	-	0.170	-	4
e	2.	29	0.090	BSC	
L	8.89	9.60	0.350	0.380	
L1	1.91	2.29	0.075	0.090	
L2	0.89	1.27	0.035	0.050	4
L3	1.14	1.52	0.045	0.060	5
ø1	0.	15	0.	15'	
			1		

DIMENSIONING AND TOLERANCING PER ASME Y14.5 M- 1994. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

LEAD DIMENSION UNCONTROLLED IN L3.

CONTROLLING DIMENSION : INCHES.

DIMENSION 61, 63 APPLY TO BASE METAL ONLY.

OUTLINE CONFORMS TO JEDEC OUTLINE TO-251AA.

DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED

0.005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

THERMAL PAD CONTOUR OPTION WITHIN DIMENSION 64, L2, E1 & D1.

LEAD ASSIGNMENTS

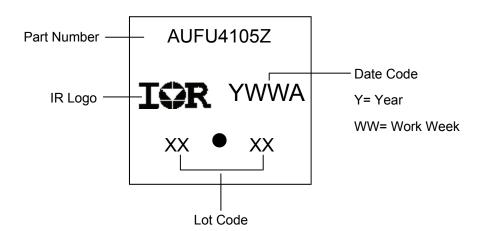
<u>HEXFET</u>

1.— GATE 2.— DRAIN

3.- SOURCE

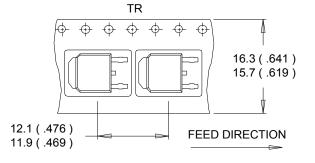
4.- DRAIN

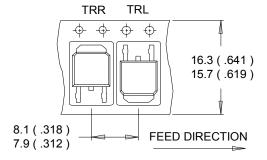
## I-Pak (TO-251AA) Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

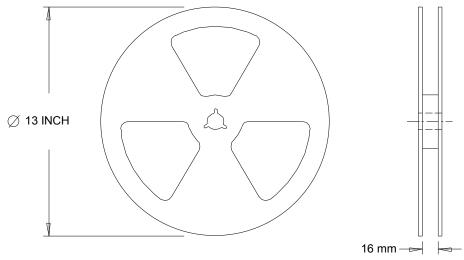
## D-Pak (TO-252AA) Tape & Reel Information (Dimensions are shown in millimeters (inches))





#### NOTES :

- 1. CONTROLLING DIMENSION : MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS ( INCHES ).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



#### NOTES : 1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



## **Qualification Information**

		Automotive (per AEC-Q101)				
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.				
Moisture Sensitivity Level		D-Pak	MSL1			
		I-Pak	WISE I			
	Machine Model		Class M2 (+/-200V) <sup>†</sup>			
		AEC-Q101-002				
		Class H1A (+/-500V) <sup>†</sup>				
ESD	Human Body Model	AEC-Q101-001				
		Class C5 (+/-1125V) <sup>†</sup>				
	Charged Device Model	AEC-Q101-005				
RoHS Compliant		Yes				

+ Highest passing voltage.

#### **Revision History**

Date	Comments			
12/1/2015	Updated datasheet with corporate template			
12/1/2013	Corrected ordering table on page 1.			

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